

Agarose (single)

Description

Diffraction Diagram

Fig.1 X-ray diffraction patterns from WHT film of agarose.

(a) Oriented under second type of stretching procedure between 80 and 100Å°C. Patterns show high degree of orientation and crystallization with a layer line spacing of 3.552 nm and a clearly defined meridional on the fourth layer line at spacing 0.888 nm.

*Permission Pending for Diffraction Diagrams

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Fig.2 X-ray diffraction patterns from DMAA high-temperature (DHT) film.

(a) Oriented using type 2 stretching procedure at 42-53Å°C. Substantially improved crystallinity showing layer lines at spacing 2.919 nm with a meridional on the third layer line at spacing 0.973 nm.

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(b) Similar to (b) but with slightly different layer line spacing of 2.815 nm and changes in the intensity of various reflections, especially on equator.

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